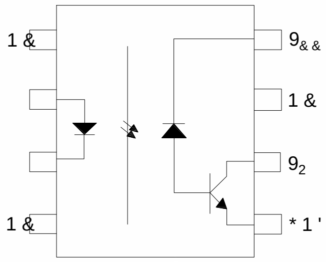
7KH SURGXFWV DUHHG0%RSWKRJFKRXSOHHU
LV D VPDOO RXWOLHQHHRFRXXSOHUFHVXPLWX
,W FRQVLVWV RI D KLJK RXWSXW SRZH ' RSWL
WR D KLJK VSHHG SKRWRWRGLFRKGH WWUDLQ
SODVWLF :623 DQG JXHHUSDQWHHGHLWWDFQ
D FOHDUDQFH RI • PPWLRQQG WDKLEQVKVV
7KHUHIRUH LW PHHHGVLQWKHDWWLRQRFMG HQW
RI LQWHUQDWLRQDO VDIHW\ VWDQGDU XFWV D
LQ SURJUDPPDEOH FRQWUROOHUYHUWHU KLQJ
SRZHU VXSSOLHV

+LJK LVRODWLRQ 9506
&7,! 9
2SHUDWLQJ WHPSHUDWXUH ƒ& WR ƒ&
5($&+ 5R+6 FRPSOLDQFH
+%0 + $ 00 0 &'0 &
&4& DSSURYHG
9'(DSSURYHG
8/ DSSURYHG



/('	2XWSXW
21	/
2))	+

7HPSHUDWXUH ƒ&

Parameter		Symbol	Value	Unit
,QSXW	)RUZDUG &XUUHQW	,)		
	3HDN)RUZDUG &XUUHQW	,)3	7	$
	5HYHUVH 9ROWDJH	95		
	,QSXW 3RZHU 'LVVLSDWLRQ	3		P:
2XWSXW	6XSSO\ 9ROWDJH	&&	9	
	2XWSXW 9ROWDJH	92		

	2XWSXW &XUUHQW	,2		
	2XWSXW 3RZHU 'LVVLSDWLRQ	32	3	P:
7RWDO 3RZHU 'LVVLSDWLRQ		3WRW		P:
,VRODWLRQ 9ROWDJH		9LVR	8	9UPV
2SHUDWLQJ 7HPSHUDWXUH		7RSU	a	
-XQFWLRQ 7HPSHUDWXUH		7M		
6WRUDJH 7HPSHUDWXUH		7VWJ	a	
6ROGHULQJ 7HPSHUDWXUH		7VRO		

í ì ì

&RPPRQ 0RGH 7UDQVLHQW ,PPXQLW\ DW /RJLF +LJK	&0+	,)	P$
		9&0	9SS
		5/	N gcV V • € ˜D Gv5l

FIG.7: /RZ /HYHO 2XWSXW 9ROWDJH YV $PELHQW
7HPSHUDWXUH

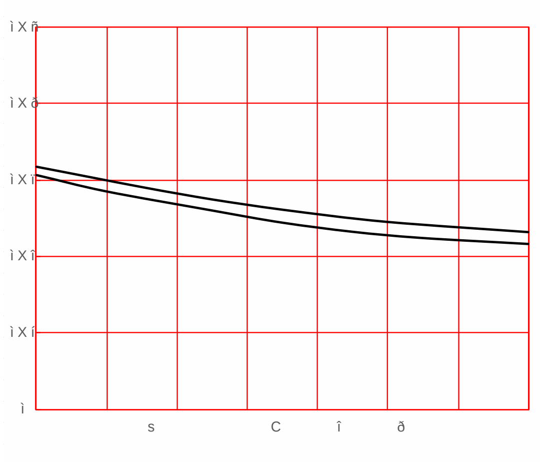


FIG.8: 3URSDJDWLRQ 'HOD\ YV /RDG
5HVLVWDQFH

Fig.10: Test Circuit of tPHL, tPLH

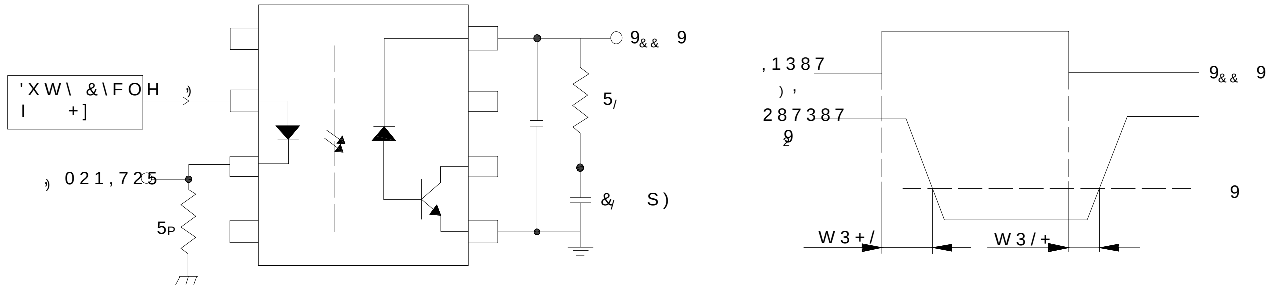
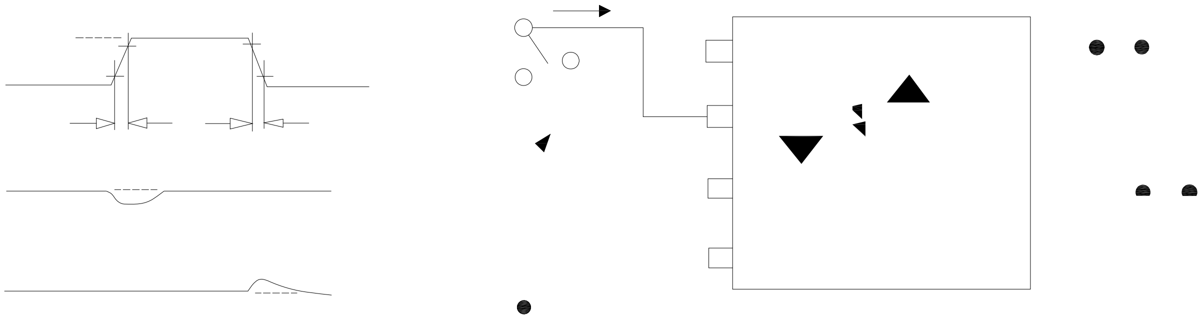
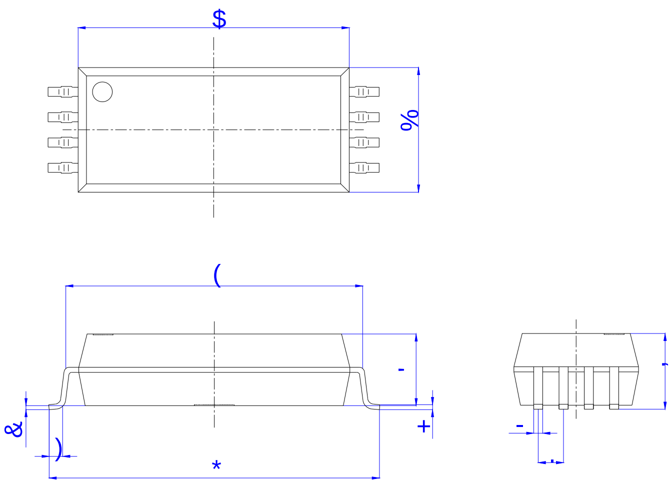


Fig.11: Test Circuit for Transient Immunity and Typical Waveforms





5HI	'LPHQVLRQV					
	0LOOLPHWHUV			,QFKHV		
	0LQ	7\S	0D[	0LQ	7\S	0D[
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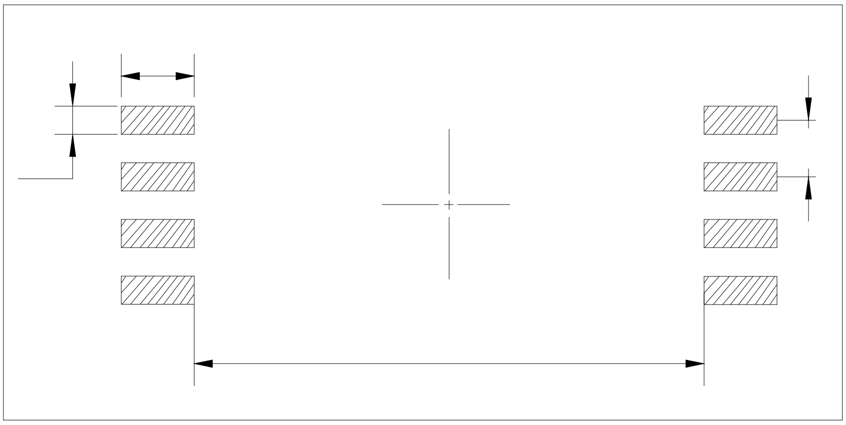

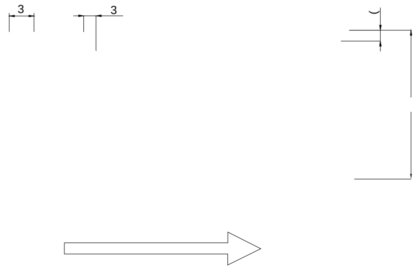
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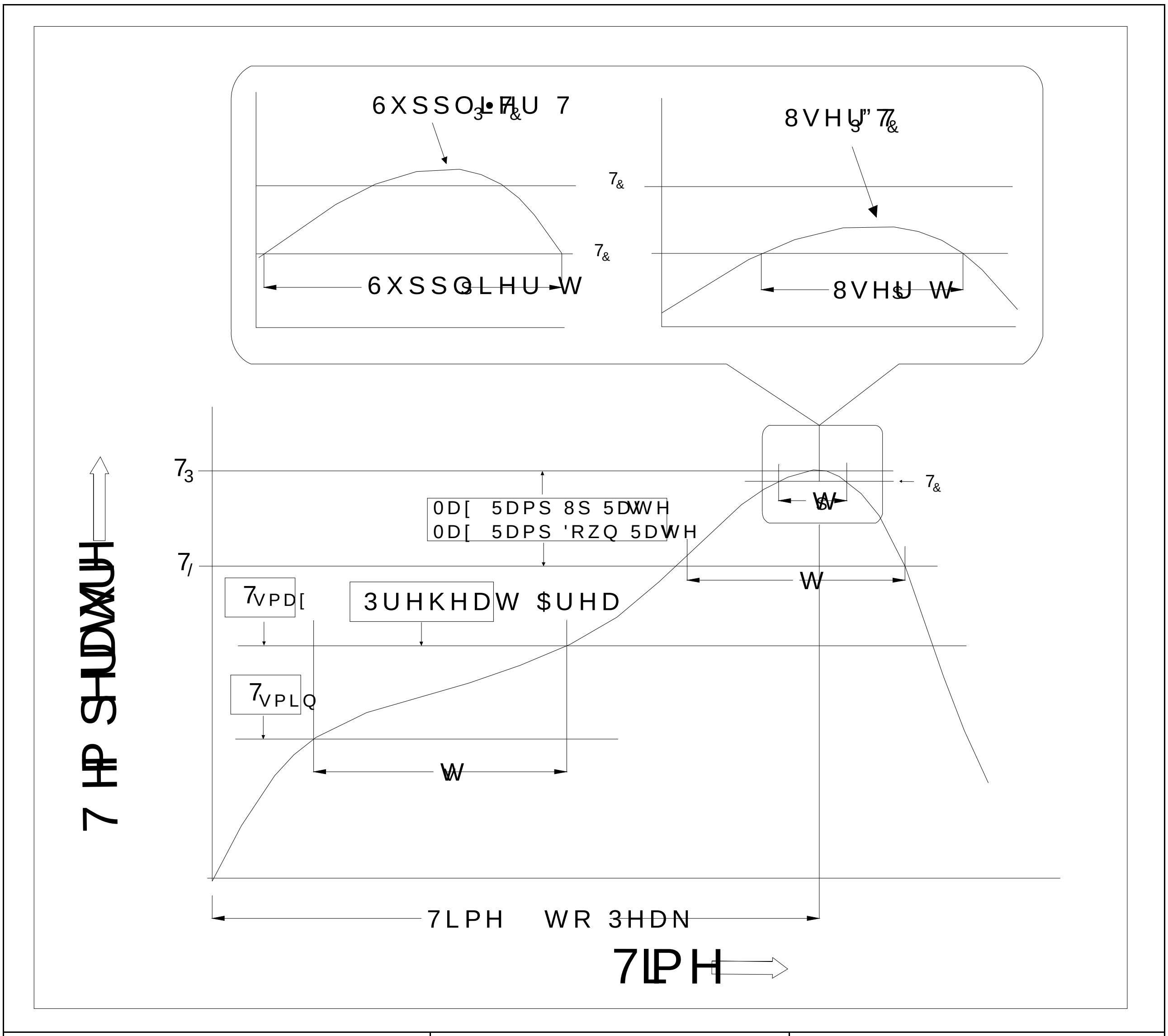
3



Profile Feature	Sn-Pb Assembly Profile	Pb-Free Assembly Profile
7HPSHUDWXUH 0LQ	7VPLQ	
7HPSHUDWXUH 0D[	7VPD[	

1RWH

5HIORZ VROGHULQJ LV UHFRPPHQGHG [illegible]

$YRLG GLUHFW FR[illegible] H[FHHGLQJ LWV PD
VWRUDJH WHPSHUDWXUH

$SSOLFDWLRQ R[illegible] WHPSHUDWXUHV ,Q V
VFHQDULRV DQ[illegible] 1

(QVXUH WKH FRPSRQHQW KDV FRROHG [illegible]
PDQXIDFWXULQJ VWHSV

7KH FRPSRQHQW [illegible] VWRUHG XQGHU

06I OHYH G 06I S